

<b>Notice of References Cited</b>	Application/Control No. 10/574,568	Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL.	
	Examiner Keath T. Chen	Art Unit 1709	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0077150	04-2003	Matsuda et al.	414/217
*	B	US-5,820,683	10-1998	Ishii et al.	118/728
*	C	US-5,169,684	12-1992	Takagi, Youji	427/248.1
*	D	US-5,651,670	07-1997	Okase et al.	432/5
*	E	US-6,287,112	09-2001	Van Voorst Vader et al.	432/258
*	F	US-5,316,472	05-1994	Niino et al.	432/241
*	G	US-2004/0099219	05-2004	Park et al.	118/728
*	H	US-2002/0070095	06-2002	Osaka et al.	198/394
*	I	US-4,745,088	05-1988	Inoue et al.	117/98
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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